MAX.

600D

600E

600F

600

16

140

UNIT

V

A

А

Three quadrant triacs guaranteed commutation

BTA216B series D, E and F

GENERAL DESCRIPTION

Passivated guaranteed commutation triacs in a plastic envelope suitable for surface mounting, intended for use in motor control circuits or with other highly inductive loads. These devices balance the requirements of commutation performance and gate sensitivity. The "sensitive gate" E series and "logic level" D series are intended for interfacing with low power drivers, including micro controllers.

DESCRIPTION

PINNING - SOT404

main terminal 1

main terminal 2

main terminal 2

PIN

1

2

3

mb

QUICK REFERENCE DATA

voltages

current

PARAMETER

SYMBOL

V_{DRM}

I_{T(RMS)}

PIN CONFIGURATION

ITSM



BTA216B-

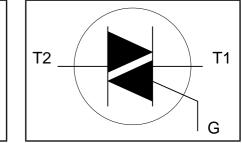
BTA216B-

BTA216B-

Repetitive peak off-state

Non-repetitive peak on-state

RMŠ on-state current



LIMITING VALUES

gate

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{DRM}	Repetitive peak off-state voltages		-	600 ¹	V
I _{T(RMS)} I _{TSM}	RMS on-state current Non-repetitive peak on-state current	full sine wave; $T_{mb} \le 99 \degreeC$ full sine wave; $T_j = 25 \degreeC$ prior to	-	16	A
l²t dI _⊤ /dt	I ² t for fusing Repetitive rate of rise of on-state current after	surge t = 20 ms t = 16.7 ms t = 10 ms $I_{TM} = 20 \text{ A}; I_G = 0.2 \text{ A};$ $dI_G/dt = 0.2 \text{ A}/\mu \text{s}$	-	140 150 98 100	Α Α Α²s Α/μs
I _{GM} P _{GM} P _{G(AV)}	triggering Peak gate current Peak gate power Average gate power	over any 20 ms period	- - -	2 5 0.5	A W W
T _{stg} T _j	Storage temperature Operating junction temperature	F	-40 -	150 125	°C C

¹ Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 15 $A/\mu s$.

BTA216B series D, E and F

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R _{th j-mb} R _{th j-a}	Thermal resistance junction to mounting base Thermal resistance junction to ambient	full cycle half cycle minimum footprint, FR4 board	-	- - 55	1.2 1.7 -	K/W K/W K/W

STATIC CHARACTERISTICS

 $T_j = 25$ °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.		MAX.		UNIT
		BTA216B-		D	E	F	
I _{GT}	Gate trigger current ²	V _D = 12 V; I _T = 0.1 A T2+ G+ T2+ G- T2- G-	- - -	5 5 5	10 10 10	25 25 25	mA mA mA
IL.	Latching current	V _D = 12 V; I _{GT} = 0.1 A T2+ G+ T2+ G- T2- G-	- - -	15 25 25	25 30 30	30 40 40	mA mA mA
I _H	Holding current	$V_{\rm D} = 12 \text{ V}; \text{ I}_{\rm GT} = 0.1 \text{ A}$	-	15	25	30	mA
			D, E, F				
V _T V _{GT}	On-state voltage Gate trigger voltage	$I_{T} = 20 \text{ A}$ $V_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}$ $V_{D} = 400 \text{ V}; I_{T} = 0.1 \text{ A};$	- - 0.25		1.5 1.5 -		V V V
I _D	Off-state leakage current	$\begin{bmatrix} T_j = 125 \ ^{\circ}C \\ V_D = V_{DRM(max)}; \ T_j = 125 \ ^{\circ}C \end{bmatrix}$	-		0.5		mA

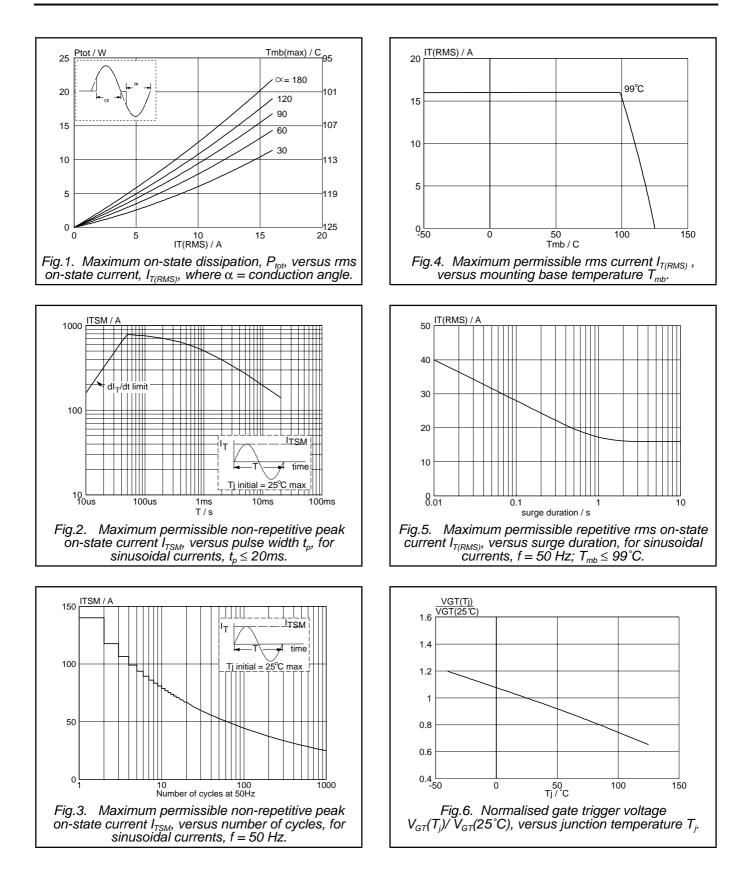
DYNAMIC CHARACTERISTICS

 $T_i = 25$ °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.		MAX.	UNIT	
		BTA216B-	D	E	F		
dV _D /dt	Critical rate of rise of off-state voltage	$V_{DM} = 67\% V_{DRM(max)};$ $T_j = 110$ °C; exponential	30	60	70	-	V/µs
dl _{com} /dt	Critical rate of change of commutating current	waveform; gate open circuit $V_{DM} = 400 \text{ V}; \text{ T}_{j} = 125 \text{ °C};$ $I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 10V/\mu s; \text{ gate}$ open circuit	2.5	6.2	18	-	A/ms
dl _{com} /dt	Critical rate of change of commutating current	$V_{DM} = 400 \text{ V}; \text{ T}_{j} = 125 ^{\circ}\text{C};$ $I_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 0.1 \text{V}/\mu\text{s}; \text{ gate}$ open circuit	12	20	50	-	A/ms

² Device does not trigger in the T2-, G+ quadrant.

BTA216B series D, E and F



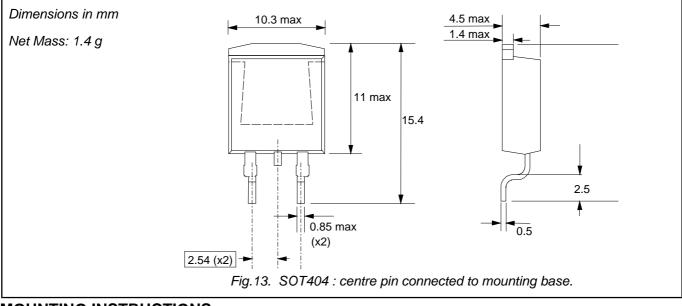
BTA216B series D, E and F

Three quadrant triacs guaranteed commutation

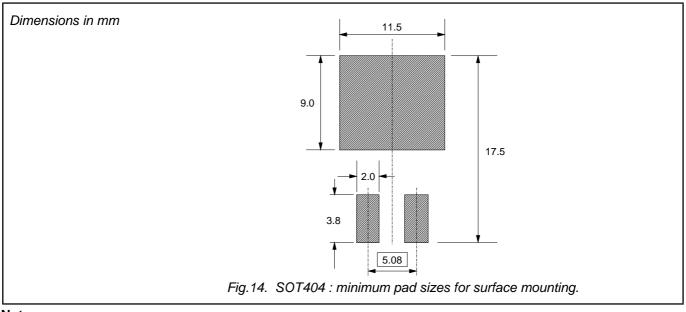
IT / A IGT(Tj) IGT(25°C) 50 Tj = 125 C Tj = 25 C 3 — T2+ G+ — T2+ Gtyp ma - T2- G-40 2.5 Vo = 1.195 V Rs = 0.018 Ohms 2 30 1.5 20 1 10 0.5 0 _0 0 1.5 VT / V 150 0.5 2 2.5 3 -50 0 тј/°С 100 1 Fig.7. Normalised gate trigger current $I_{GT}(T_j)/I_{GT}(25^{\circ}C)$, versus junction temperature T_j . Fig.10. Typical and maximum on-state characteristic. 10 Eth j-mb (K/W) IL(Tj) IL(25°C) 3 25 1 bidirectional 2 0.1 1.5 → ^tp 1 0.01 0.5 0.001 – 10us 0 -50 0.1ms 10ms 0.1s 1s 10s 50 Tj /℃ 1ms 0 100 150 tp/s Normalised latching current $I_L(T_{\underline{i}})/I_L(25^{\circ}C)$, Fig.11. Transient thermal impedance $Z_{th j-mb}$, versus Fig.8. versus junction temperature T_{i} pulse width t_{p} dlcom/dt (A/ms) IH(Tj) 100 3 IH(25°C F TYPE - E TYPE D TYPE 2.5 2 10 1.5 1 0.5 1 0└ -50 50 Tj /℃ 20 40 60 100 120 140 100 150 0 80 Tj/°C Fig.9. Normalised holding current $I_H(T_j)/I_H(25^{\circ}C)$, versus junction temperature T_j . Fig. 12. Mimimum, critical rate of change of commutating current dI_{com}/dt versus junction temperature, $dV_{com}/dt = 10V/\mu s$.

BTA216B series D, E and F

MECHANICAL DATA



MOUNTING INSTRUCTIONS



Notes

1. Plastic meets UL94 V0 at 1/8".

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DEFINITIONS

DATA SHEET STATUS						
DATA SHEETPRODUCTDSTATUS3STATUS4		DEFINITIONS				
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice				
Preliminary data Qualification		This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product				
Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Changes will be communicated according to the Customer Product/Process Change Notification (CPCN) procedure SNW-SQ-650A				

Limiting values

Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information

Where application information is given, it is advisory and does not form part of the specification.

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³ Please consult the most recently issued datasheet before initiating or completing a design.

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